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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	120MHz
Connectivity	CANbus, I²C, IrDA, LINbus, MMC, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I²S, LCD, POR, PWM, WDT
Number of I/O	51
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	132K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f205ret7tr

3.4 Embedded Flash memory

The STM32F20x devices embed a 128-bit wide Flash memory of 128 Kbytes, 256 Kbytes, 512 Kbytes, 768 Kbytes or 1 Mbyte available for storing programs and data.

The devices also feature 512 bytes of OTP memory that can be used to store critical user data such as Ethernet MAC addresses or cryptographic keys.

3.5 CRC (cyclic redundancy check) calculation unit

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code from a 32-bit data word and a fixed generator polynomial.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a software signature during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

3.6 Embedded SRAM

All STM32F20x products embed:

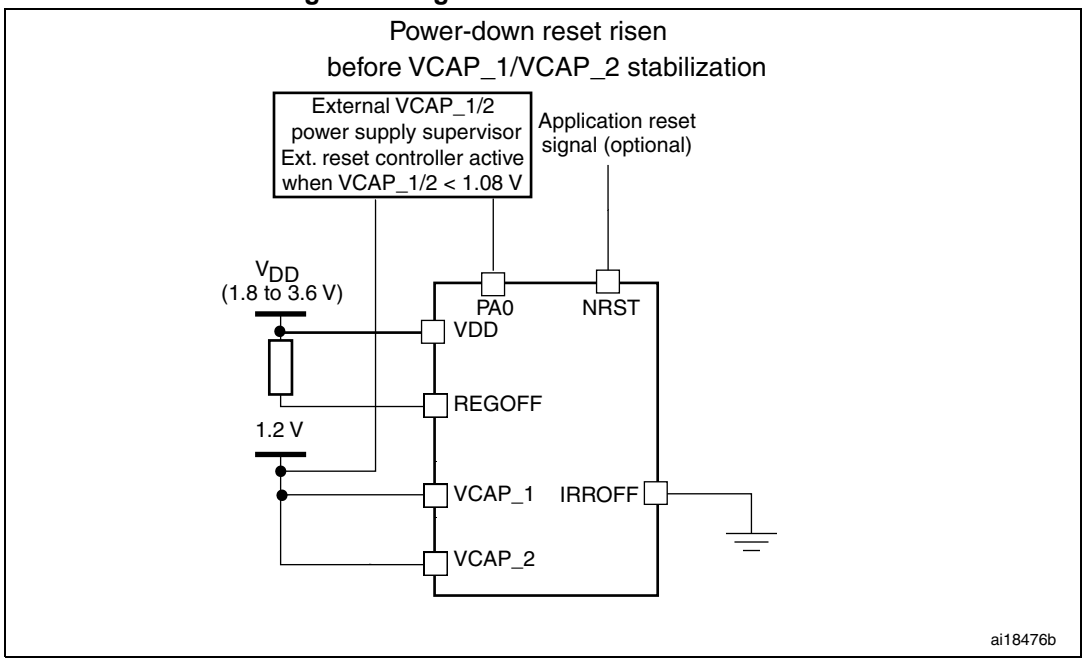
- Up to 128 Kbytes of system SRAM accessed (read/write) at CPU clock speed with 0 wait states
- 4 Kbytes of backup SRAM.

  The content of this area is protected against possible unwanted write accesses, and is retained in Standby or V_{BAT} mode.

3.7 Multi-AHB bus matrix

The 32-bit multi-AHB bus matrix interconnects all the masters (CPU, DMAs, Ethernet, USB HS) and the slaves (Flash memory, RAM, FSMC, AHB and APB peripherals) and ensures a seamless and efficient operation even when several high-speed peripherals work simultaneously.

Figure 6. Regulator OFF/internal reset ON



The following conditions must be respected:

- V_{DD} should always be higher than V_{CAP_1} and V_{CAP_2} to avoid current injection between power domains.
- If the time for V_{CAP_1} and V_{CAP_2} to reach 1.08 V is faster than the time for V_{DD} to reach 1.8 V, then PA0 should be kept low to cover both conditions: until V_{CAP_1} and V_{CAP_2} reach 1.08 V and until V_{DD} reaches 1.8 V (see *Figure 8*).
- Otherwise, If the time for V_{CAP_1} and V_{CAP_2} to reach 1.08 V is slower than the time for V_{DD} to reach 1.8 V, then PA0 should be asserted low externally (see *Figure 9*).
- If V_{CAP_1} and V_{CAP_2} go below 1.08 V and V_{DD} is higher than 1.8 V, then a reset must be asserted on PA0 pin.

Regulator OFF/internal reset OFF

On WLCSP64+2 package, this mode activated by connecting REGOFF to V_{SS} and IRROFF to V_{DD}. IRROFF cannot be activated in conjunction with REGOFF. This mode is available only on the WLCSP64+2 package. It allows to supply externally a 1.2 V voltage source through V_{CAP_1} and V_{CAP_2} pins. In this mode, the integrated power-on reset (POR)/ power-down reset (PDR) circuitry is disabled.

An external power supply supervisor should monitor both the external 1.2 V and the external V_{DD} supply voltage, and should maintain the device in reset mode as long as they remain below a specified threshold. The V_{DD} specified threshold, below which the device must be maintained under reset, is 1.8 V. This supply voltage can drop to 1.7 V when the device operates in the 0 to 70 °C temperature range. A comprehensive set of power-saving modes allows the design of low-power applications.

Table 8. STM32F20x pin and ball definitions

Pins						Pin name (function after reset)(1)	Pin type	I/O structure	Note	Alternate functions	Additional functions
LQFP64	WLCSP64+2	LQFP100	LQFP144	LQFP176	UFBGA176						
-	-	1	1	1	A2	PE2	I/O	FT	-	TRACECLK, FSMC_A23, ETH_MII_TXD3, EVENTOUT	-
-	-	2	2	2	A1	PE3	I/O	FT	-	TRACED0,FSMC_A19, EVENTOUT	-
-	-	3	3	3	B1	PE4	I/O	FT	-	TRACED1,FSMC_A20, DCMI_D4, EVENTOUT	-
-	-	4	4	4	B2	PE5	I/O	FT	-	TRACED2, FSMC_A21, TIM9_CH1, DCMI_D6, EVENTOUT	-
-	-	5	5	5	B3	PE6	I/O	FT	-	TRACED3, FSMC_A22, TIM9_CH2, DCMI_D7, EVENTOUT	-
1	A9	6	6	6	C1	V_{BAT}	S		-	-	-
-	-	-	-	7	D2	PI8	I/O	FT	(2)(3)	EVENTOUT	RTC_AF2
2	B8	7	7	8	D1	PC13	I/O	FT	(2)(3)	EVENTOUT	RTC_AF1
3	B9	8	8	9	E1	PC14/OSC32_IN (PC14)	I/O	FT	(2)(3)	EVENTOUT	OSC32_IN(4)
4	C9	9	9	10	F1	PC15-OSC32_OUT (PC15)	I/O	FT	(2)(3)	EVENTOUT	OSC32_OUT(4)
-	-	-	-	11	D3	PI9	I/O	FT	-	CAN1_RX,EVENTOUT	-
-	-	-	-	12	E3	PI10	I/O	FT	-	ETH_MII_RX_ER, EVENTOUT	-
-	-	-	-	13	E4	PI11	I/O	FT	-	OTG_HS_ULPI_DIR, EVENTOUT	-
-	-	-	-	14	F2	V_{SS}	S		-	-	-
-	-	-	-	15	F3	V_{DD}	S		-	-	-
-	-	-	10	16	E2	PF0	I/O	FT	-	FSMC_A0, I2C2_SDA, EVENTOUT	-
-	-	-	11	17	H3	PF1	I/O	FT	-	FSMC_A1, I2C2_SCL, EVENTOUT	-
-	-	-	12	18	H2	PF2	I/O	FT	-	FSMC_A2, I2C2_SMBA, EVENTOUT	-
-	-	-	13	19	J2	PF3	I/O	FT	(4)	FSMC_A3, EVENTOUT	ADC3_IN9

Table 8. STM32F20x pin and ball definitions (continued)

Pins						Pin name (function after reset)(1)	Pin type	I/O structure	Note	Alternate functions	Additional functions
LQFP64	WLCSP64+2	LQFP100	LQFP144	LQFP176	UFBGA176						
13	-	22	33	39	R1	V_{DDA}	S	-	-	-	-
14	E7	23	34	40	N3	PA0-WKUP (PA0)	I/O	FT	(4)(5)	USART2_CTS, UART4_TX, ETH_MII_CRS, TIM2_CH1_ETR, TIM5_CH1, TIM8_ETR, EVENTOUT	ADC123_IN0, WKUP
15	H8	24	35	41	N2	PA1	I/O	FT	(4)	USART2_RTS, UART4_RX, ETH_RMII_REF_CLK, ETH_MII_RX_CLK, TIM5_CH2, TIM2_CH2, EVENTOUT	ADC123_IN1
16	J9	25	36	42	P2	PA2	I/O	FT	(4)	USART2_TX,TIM5_CH3, TIM9_CH1, TIM2_CH3, ETH_MDIO, EVENTOUT	ADC123_IN2
-	-	-	-	43	F4	PH2	I/O	FT	-	ETH_MII_CRS, EVENTOUT	-
-	-	-	-	44	G4	PH3	I/O	FT	-	ETH_MII_COL, EVENTOUT	-
-	-	-	-	45	H4	PH4	I/O	FT	-	I2C2_SCL, OTG_HS_ULPI_NXT, EVENTOUT	-
-	-	-	-	46	J4	PH5	I/O	FT	-	I2C2_SDA, EVENTOUT	-
17	G7	26	37	47	R2	PA3	I/O	FT	(4)	USART2_RX, TIM5_CH4, TIM9_CH2, TIM2_CH4, OTG_HS_ULPI_D0, ETH_MII_COL, EVENTOUT	ADC123_IN3
18	F1	27	38	48	-	V_{SS}	S	-	-	-	-
	H7				L4	REGOFF	I/O	-	-	-	-
19	E1	28	39	49	K4	V_{DD}	S	-	-	-	-
20	J8	29	40	50	N4	PA4	I/O	TTa	(4)	SPI1_NSS, SPI3_NSS, USART2_CK, DCMI_HSYNC, OTG_HS_SOF, I2S3_WS, EVENTOUT	ADC12_IN4, DAC_OUT1
21	H6	30	41	51	P4	PA5	I/O	TTa	(4)	SPI1_SCK, OTG_HS_ULPI_CK, TIM2_CH1_ETR, TIM8_CH1N, EVENTOUT	ADC12_IN5, DAC_OUT2

Table 8. STM32F20x pin and ball definitions (continued)

Pins						Pin name (function after reset)[1]	Pin type	I/O structure	Note	Alternate functions	Additional functions
LQFP64	WLCSP64+2	LQFP100	LQFP144	LQFP176	UFBGA176						
-	-	98	142	170	A3	PE1	I/O	FT	-	FSMC_NBL1, DCMI_D3, EVENTOUT	-
-	-	-	-	-	D5	V_{SS}	S	-	-	-	-
63	D8	-	-	-	-	V_{SS}	S	-	-	-	-
-	-	99	143	171	C6	RFU	-	-	(7)	-	-
64	D9	100	144	172	C5	V_{DD}	S	-	-	-	-
-	-	-	-	173	D4	PI4	I/O	FT	-	TIM8_BKIN, DCMI_D5, EVENTOUT	-
-	-	-	-	174	C4	PI5	I/O	FT	-	TIM8_CH1, DCMI_VSYNC, EVENTOUT	-
-	-	-	-	175	C3	PI6	I/O	FT	-	TIM8_CH2, DCMI_D6, EVENTOUT	-
-	-	-	-	176	C2	PI7	I/O	FT	-	TIM8_CH3, DCMI_D7, EVENTOUT	-
-	C8	-	-	-	-	IRROFF	I/O	-	-	-	-

1. Function availability depends on the chosen device.
2. PC13, PC14, PC15 and PI8 are supplied through the power switch. Since the switch only sinks a limited amount of current (3 mA), the use of GPIOs PC13 to PC15 and PI8 in output mode is limited: the speed should not exceed 2 MHz with a maximum load of 30 pF and these I/Os must not be used as a current source (e.g. to drive an LED).
3. Main function after the first backup domain power-up. Later on, it depends on the contents of the RTC registers even after reset (because these registers are not reset by the main reset). For details on how to manage these I/Os, refer to the RTC register description sections in the STM32F20x and STM32F21x reference manual, available from the STMicroelectronics website: www.st.com.
4. FT = 5 V tolerant except when in analog mode or oscillator mode (for PC14, PC15, PH0 and PH1).
5. If the device is delivered in an UFBGA176 package and if the REGOFF pin is set to V_{DD} (Regulator OFF), then PA0 is used as an internal Reset (active low).
6. FSMC_NL pin is also named FSMC_NADV on memory devices.
7. RFU means “reserved for future use”. This pin can be tied to V_{DD},V_{SS} or left unconnected.

Table 9. FSMC pin definition

Pins	FSMC				LQFP100
	CF	NOR/PSRAM/SRAM	NOR/PSRAM Mux	NAND 16 bit	
PE2	-	A23	A23	-	Yes
PE3	-	A19	A19	-	Yes
PE4	-	A20	A20	-	Yes

Table 9. FSMC pin definition (continued)

Pins	FSMC				LQFP100
	CF	NOR/PSRAM/SRAM	NOR/PSRAM Mux	NAND 16 bit	
PE5	-	A21	A21	-	Yes
PE6	-	A22	A22	-	Yes
PF0	A0	A0	-	-	-
PF1	A1	A1	-	-	-
PF2	A2	A2	-	-	-
PF3	A3	A3	-	-	-
PF4	A4	A4	-	-	-
PF5	A5	A5	-	-	-
PF6	NIORD	-	-	-	-
PF7	NREG	-	-	-	-
PF8	NIOWR	-	-	-	-
PF9	CD	-	-	-	-
PF10	INTR	-	-	-	-
PF12	A6	A6	-	-	-
PF13	A7	A7	-	-	-
PF14	A8	A8	-	-	-
PF15	A9	A9	-	-	-
PG0	A10	A10	-	-	-
PG1	-	A11	-	-	-
PE7	D4	D4	DA4	D4	Yes
PE8	D5	D5	DA5	D5	Yes
PE9	D6	D6	DA6	D6	Yes
PE10	D7	D7	DA7	D7	Yes
PE11	D8	D8	DA8	D8	Yes
PE12	D9	D9	DA9	D9	Yes
PE13	D10	D10	DA10	D10	Yes
PE14	D11	D11	DA11	D11	Yes
PE15	D12	D12	DA12	D12	Yes
PD8	D13	D13	DA13	D13	Yes
PD9	D14	D14	DA14	D14	Yes
PD10	D15	D15	DA15	D15	Yes
PD11	-	A16	A16	CLE	Yes
PD12	-	A17	A17	ALE	Yes

Table 10. Alternate function mapping (continued)

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF014	AF15
		SYS	TIM1/2	TIM3/4/5	TIM8/9/10/11	I2C1/I2C2/I2C3	SPI1/SPI2/I2S2	SPI3/I2S3	USART1/2/3	UART4/5/ USART6	CAN1/CAN2/ TIM12/13/14	OTG_FS/ OTG_HS	ETH	FSMC/SDIO/ OTG_HS	DCMI		
Port B	PB0	-	TIM1_CH2N	TIM3_CH3	TIM8_CH2N	-	-	-	-	-	-	OTG_HS_ULPI_D1	ETH _MII_RXD2	-	-	-	EVENTOUT
	PB1	-	TIM1_CH3N	TIM3_CH4	TIM8_CH3N	-	-	-	-	-	-	OTG_HS_ULPI_D2	ETH _MII_RXD3	-	-	-	EVENTOUT
	PB2	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENTOUT
	PB3	JTDO/ TRACESWO	TIM2_CH2	-	-	-	SPI1_SCK	SPI3_SCK I2S3_SCK	-	-	-	-	-	-	-	-	EVENTOUT
	PB4	JTRST	-	TIM3_CH1	-	-	SPI1_MISO	SPI3_MISO	-	-	-	-	-	-	-	-	EVENTOUT
	PB5	-	-	TIM3_CH2	-	I2C1_SMBA	SPI1_MOSI	SPI3_MOSI I2S3_SD	-	-	CAN2_RX	OTG_HS_ULPI_D7	ETH _PPS_OUT	-	DCMI_D10	-	EVENTOUT
	PB6	-	-	TIM4_CH1	-	I2C1_SCL	-	-	USART1_TX	-	CAN2_TX	-	-	-	DCMI_D5	-	EVENTOUT
	PB7	-	-	TIM4_CH2	-	I2C1_SDA	-	-	USART1_RX	-	-	-	-	FSMC_NL	DCMI_VSYNC	-	EVENTOUT
	PB8	-	-	TIM4_CH3	TIM10_CH1	I2C1_SCL	-	-	-	-	CAN1_RX	-	ETH _MII_TXD3	SDIO_D4	DCMI_D6	-	EVENTOUT
	PB9	-	-	TIM4_CH4	TIM11_CH1	I2C1_SDA	SPI2_NSS I2S2_WS	-	-	-	CAN1_TX	-	-	SDIO_D5	DCMI_D7	-	EVENTOUT
	PB10	-	TIM2_CH3	-	-	I2C2_SCL	SPI2_SCK I2S2_SCK	-	USART3_TX	-	-	OTG_HS_ULPI_D3	ETH_ MII_RX_ER	-	-	-	EVENTOUT
	PB11	-	TIM2_CH4	-	-	I2C2_SDA	-	-	USART3_RX	-	-	OTG_HS_ULPI_D4	ETH _MII_TX_EN ETH _RMII_TX_EN	-	-	-	EVENTOUT
	PB12	-	TIM1_BKIN	-	-	I2C2_SMBA	SPI2_NSS I2S2_WS	-	USART3_CK	-	CAN2_RX	OTG_HS_ULPI_D5	ETH _MII_TXD0 ETH _RMII_TXD0	OTG_HS_ID	-	-	EVENTOUT
	PB13	-	TIM1_CH1N	-	-	-	SPI2_SCK I2S2_SCK	-	USART3_CTS	-	CAN2_TX	OTG_HS_ULPI_D6	ETH _MII_TXD1 ETH _RMII_TXD1	-	-	-	EVENTOUT
	PB14	-	TIM1_CH2N	-	TIM8_CH2N	-	SPI2_MISO	-	USART3_RTS	-	TIM12_CH1	-	-	OTG_HS_DM	-	-	EVENTOUT
	PB15	RTC_50Hz	TIM1_CH3N	-	TIM8_CH3N	-	SPI2_MOSI I2S2_SD	-	-	-	TIM12_CH2	-	-	OTG_HS_DP	-	-	EVENTOUT

Table 21. Typical and maximum current consumption in Run mode, code with data processing running from Flash memory (ART accelerator disabled)

Symbol	Parameter	Conditions	f_{HCLK}	Typ	Max(1)		Unit
				T_A = 25 °C	T_A = 85 °C	T_A = 105 °C	
I_{DD}	Supply current in Run mode	External clock(2), all peripherals enabled(3)	120 MHz	61	81	93	mA
			90 MHz	48	68	80	
			60 MHz	33	53	65	
			30 MHz	18	38	50	
			25 MHz	14	34	46	
			16 MHz(4)	10	30	42	
			8 MHz	6	26	38	
			4 MHz	4	24	36	
			2 MHz	3	23	35	
		External clock(2), all peripherals disabled	120 MHz	33	54	66	
			90 MHz	27	47	59	
			60 MHz	19	39	51	
			30 MHz	11	31	43	
			25 MHz	8	28	41	
			16 MHz(4)	6	26	38	
			8 MHz	4	24	36	
			4 MHz	3	23	35	
			2 MHz	2	23	34	

1. Guaranteed by characterization results, tested in production at V_{DD} max and f_{HCLK} max with peripherals enabled.
2. External clock is 4 MHz and PLL is on when f_{HCLK} > 25 MHz.
3. When the ADC is on (ADON bit set in the ADC_CR2 register), add an additional power consumption of 1.6 mA per ADC for the analog part.
4. In this case HCLK = system clock/2.

Figure 23. Typical current consumption vs. temperature, Run mode, code with data processing running from RAM, and peripherals ON

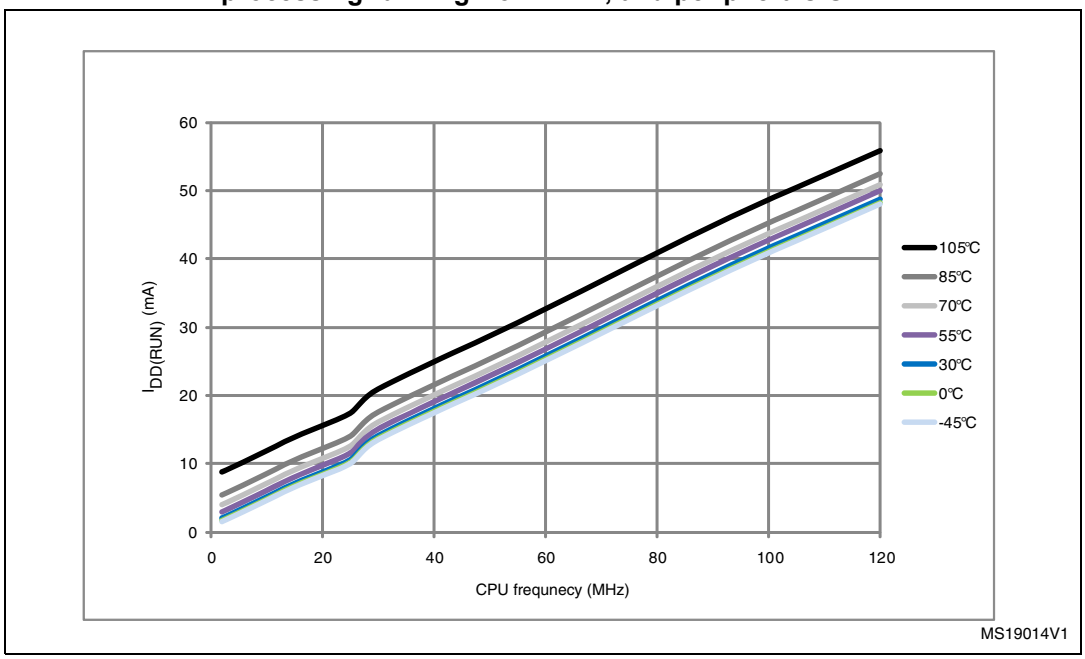


Figure 24. Typical current consumption vs. temperature, Run mode, code with data processing running from RAM, and peripherals OFF

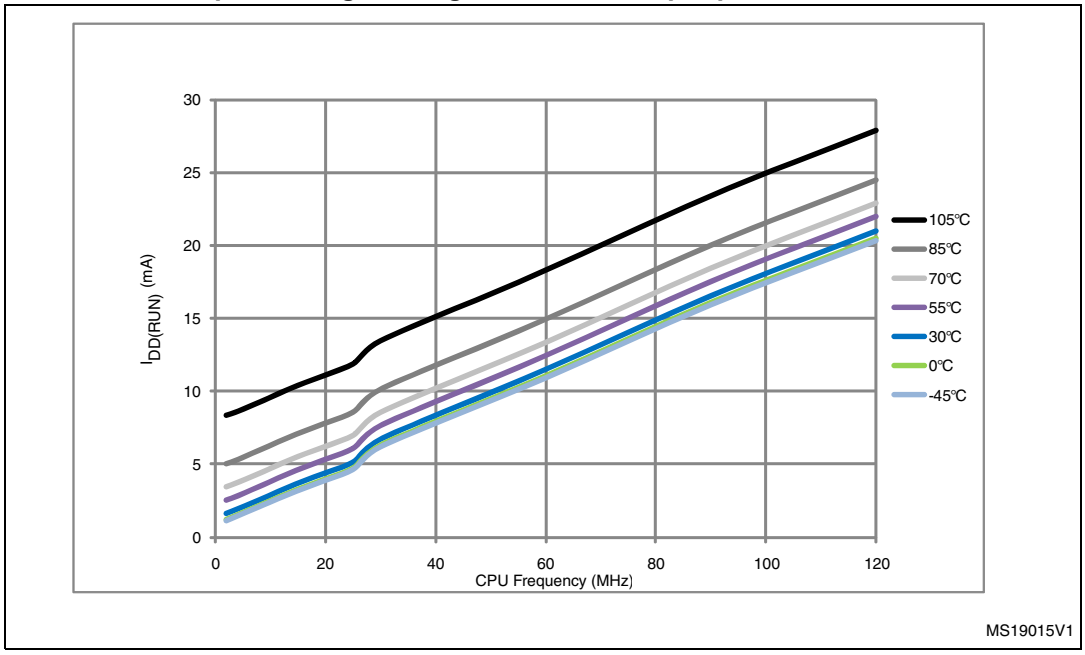


Figure 25. Typical current consumption vs. temperature, Run mode, code with data processing running from Flash, ART accelerator OFF, peripherals ON

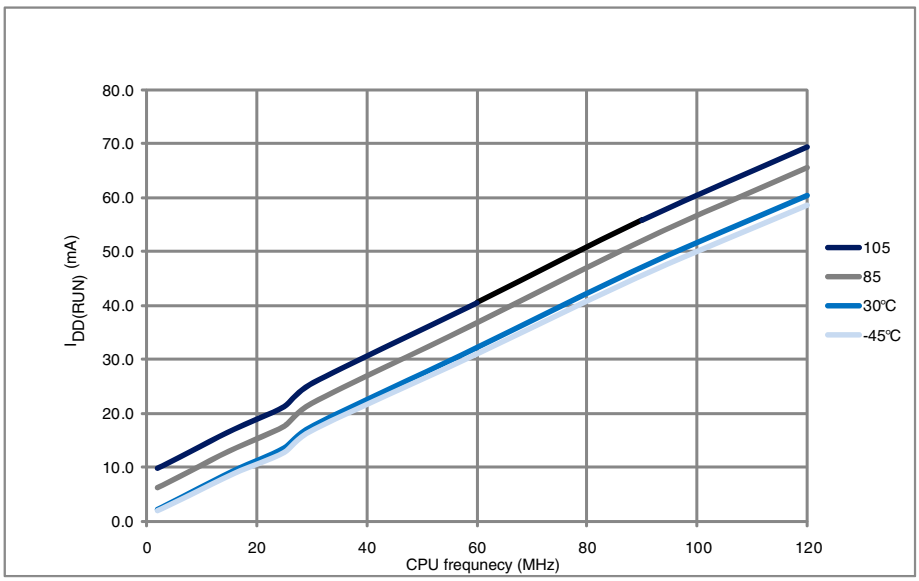


Figure 26. Typical current consumption vs. temperature, Run mode, code with data processing running from Flash, ART accelerator OFF, peripherals OFF

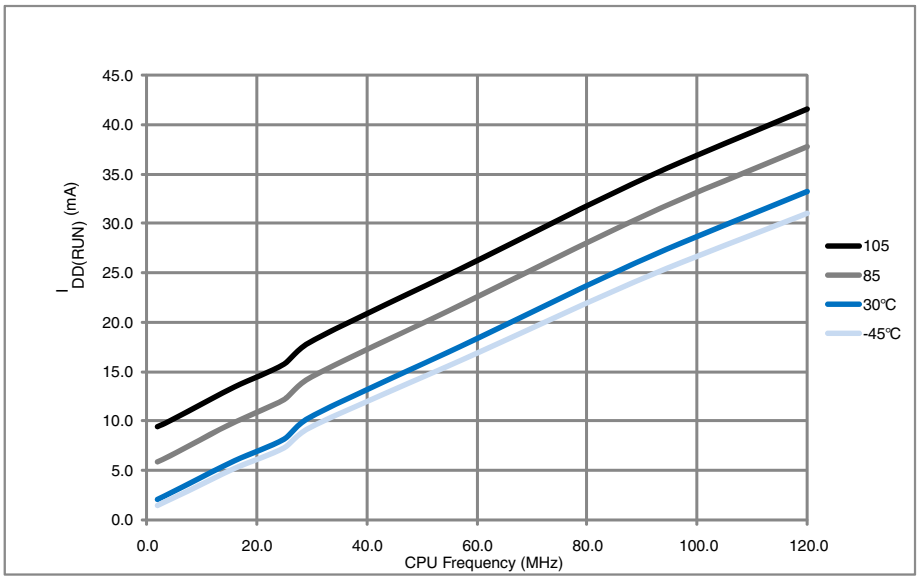
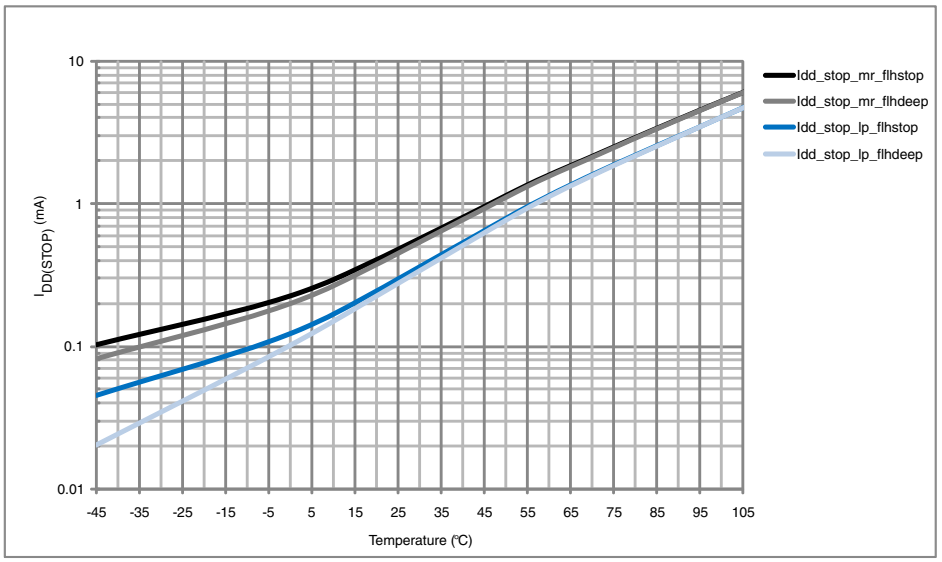


Table 23. Typical and maximum current consumptions in Stop mode

Symbol	Parameter	Conditions	Typ	Max			Unit
			T_A = 25 °C	T_A = 25 °C	T_A = 85 °C	T_A = 105 °C	
I_{DD_STOP}	Supply current in Stop mode with main regulator in Run mode	Flash in Stop mode, low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog)	0.55	1.2	11.00	20.00	mA
		Flash in Deep power down mode, low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog)	0.50	1.2	11.00	20.00	
	Supply current in Stop mode with main regulator in Low-power mode	Flash in Stop mode, low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog)	0.35	1.1	8.00	15.00	
		Flash in Deep power down mode, low-speed and high-speed internal RC oscillators and high-speed oscillator OFF (no independent watchdog)	0.30	1.1	8.00	15.00	

Figure 29. Typical current consumption vs. temperature in Stop mode



1. All typical and maximum values from table 18 and figure 26 will be reduced over time by up to 50% as part of ST continuous improvement of test procedures. New versions of the datasheet will be released to reflect these changes

Table 26. Peripheral current consumption

Peripheral[1]		Typical consumption at 25 °C	Unit
AHB1	GPIO A	0.45	mA
	GPIO B	0.43	
	GPIO C	0.46	
	GPIO D	0.44	
	GPIO E	0.44	
	GPIO F	0.42	
	GPIO G	0.44	
	GPIO H	0.42	
	GPIO I	0.43	
	OTG_HS + ULPI	3.64	
	CRC	1.17	
	BKPSRAM	0.21	
	DMA1	2.76	
	DMA2	2.85	
	ETH_MAC + ETH_MAC_TX ETH_MAC_RX ETH_MAC_PTP	2.99	
AHB2	OTG_FS	3.16	
	DCMI	0.60	
AHB3	FSMC	1.74	

Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with EIA/JESD 78A IC latch-up standard.

Table 44. Electrical sensitivities

Symbol	Parameter	Conditions	Class
LU	Static latch-up class	T_A = +105 °C conforming to JESD78A	II level A

6.3.15 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below V_{SS} or above V_{DD} (for standard, 3 V-capable I/O pins) should be avoided during normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

Functional susceptibilty to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error above a certain limit (>5 LSB TUE), out of spec current injection on adjacent pins or other functional failure (for example reset, oscillator frequency deviation).

The test results are given in *Table 45*.

Table 45. I/O current injection susceptibility(1)

Symbol	Description	Functional susceptibility		Unit
		Negative injection	Positive injection	
I_{INJ}	Injected current on BOOT0 pin	–0	NA	mA
	Injected current on NRST pin	–0	NA	
	Injected current on TTa pins: PA4 and PA5	–0	+5	
	Injected current on all FT pins	–5	NA	

1. NA stands for “not applicable”.

Note: It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative currents.

Figure 49. Ethernet SMI timing diagram

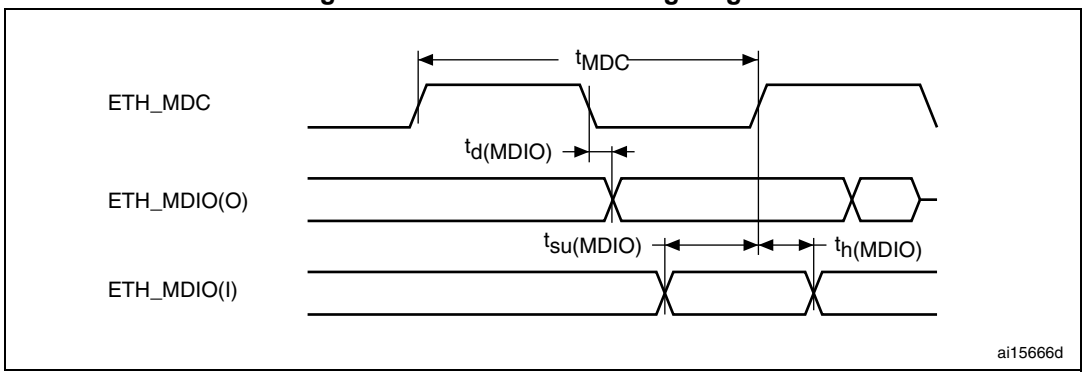


Table 63. Dynamics characteristics: Ethernet MAC signals for SMI

Symbol	Rating	Min	Typ	Max	Unit
t_{MDC}	MDC cycle time (2.38 MHz)	411	420	425	ns
$t_{d(MDIO)}$	MDIO write data valid time	6	10	13	ns
$t_{su(MDIO)}$	Read data setup time	12	-	-	ns
$t_{h(MDIO)}$	Read data hold time	0	-	-	ns

Table 64 gives the list of Ethernet MAC signals for the RMII and *Figure 50* shows the corresponding timing diagram.

Figure 50. Ethernet RMII timing diagram

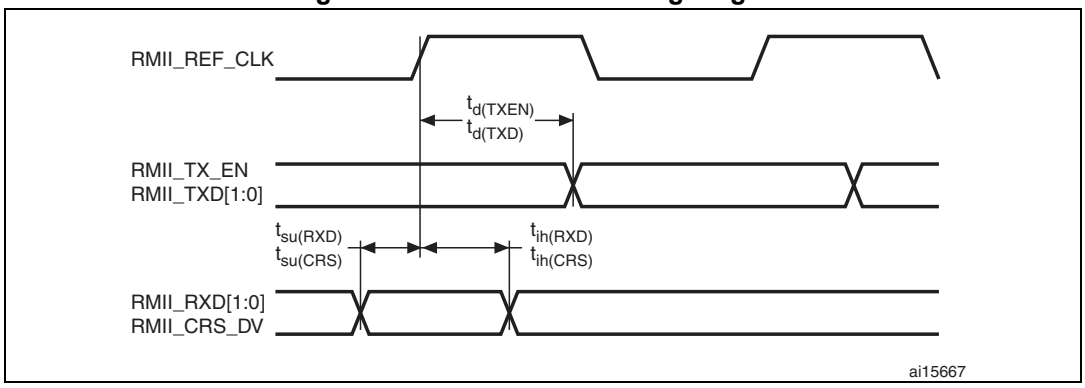


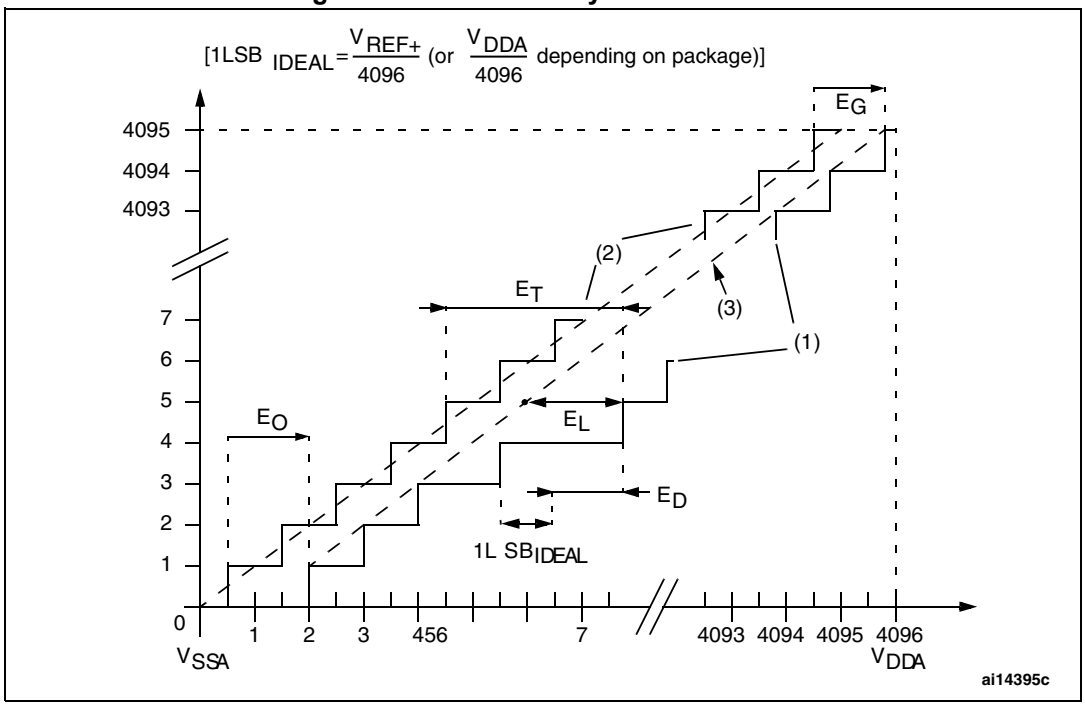
Table 64. Dynamics characteristics: Ethernet MAC signals for RMII

Symbol	Rating	Min	Typ	Max	Unit
$t_{su(RXD)}$	Receive data setup time	1	-	-	ns
$t_{ih(RXD)}$	Receive data hold time	1.5	-	-	
$t_{su(CRS)}$	Carrier sense set-up time	0	-	-	
$t_{ih(CRS)}$	Carrier sense hold time	2	-	-	
$t_{d(TXEN)}$	Transmit enable valid delay time	9	11	13	
$t_{d(TXD)}$	Transmit data valid delay time	9	11.5	14	

being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative currents.

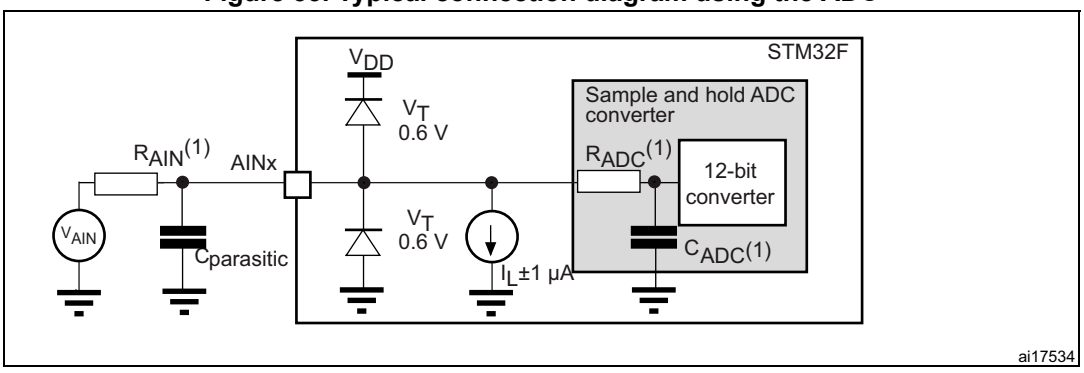
Any positive injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ in *Section 6.3.16* does not affect the ADC accuracy.

Figure 52. ADC accuracy characteristics



1. Example of an actual transfer curve.
2. Ideal transfer curve.
3. End point correlation line.
4. E_T = Total Unadjusted Error: maximum deviation between the actual and the ideal transfer curves.
   EO = Offset Error: deviation between the first actual transition and the first ideal one.
   EG = Gain Error: deviation between the last ideal transition and the last actual one.
   ED = Differential Linearity Error: maximum deviation between actual steps and the ideal one.
   EL = Integral Linearity Error: maximum deviation between any actual transition and the end point correlation line.

Figure 53. Typical connection diagram using the ADC



1. Refer to *Table 66* for the values of R_{AIN}, R_{ADC} and C_{ADC}.
2. $C_{parasitic}$ represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 7 pF). A high $C_{parasitic}$ value downgrades conversion accuracy. To remedy this, f_{ADC} should be reduced.

Table 74. Asynchronous multiplexed PSRAM/NOR read timings(1)(2) (continued)

Symbol	Parameter	Min	Max	Unit
$t_{h(Data\_NE)}$	Data hold time after FSMC_NEx high	0	-	ns
$t_{h(Data\_NOE)}$	Data hold time after FSMC_NOE high	0	-	ns

1. C_L = 30 pF.
2. Guaranteed by characterization results, not tested in production.

Figure 60. Asynchronous multiplexed PSRAM/NOR write waveforms

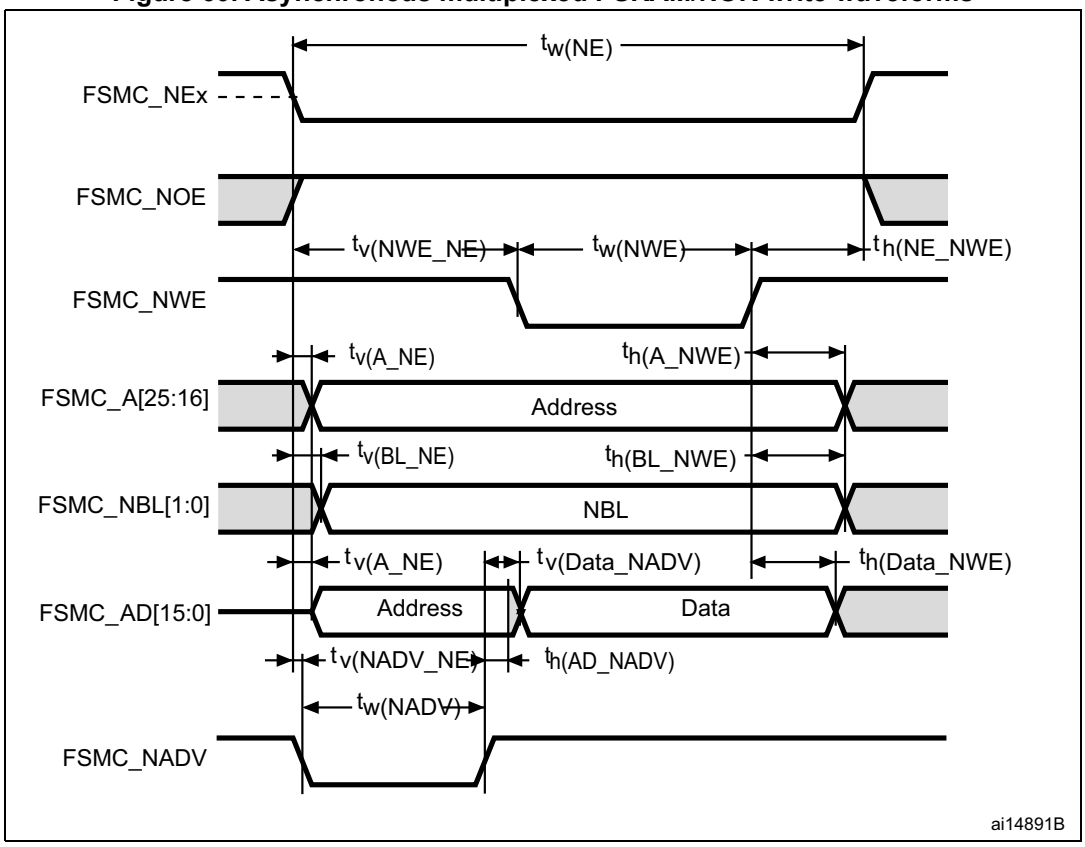


Table 75. Asynchronous multiplexed PSRAM/NOR write timings(1)(2)

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FSMC_NE low time	$4T_{HCLK}$-1	$4T_{HCLK}$+1	ns
$t_{v(NWE\_NE)}$	FSMC_NEx low to FSMC_NWE low	T_{HCLK}- 1	T_{HCLK}	ns
$t_{w(NWE)}$	FSMC_NWE low tim e	$2T_{HCLK}$	$2T_{HCLK}$+1	ns
$t_{h(NE\_NWE)}$	FSMC_NWE high to FSMC_NE high hold time	T_{HCLK}- 1	-	ns
$t_{v(A\_NE)}$	FSMC_NEx low to FSMC_A valid	-	0	ns
$t_{v(NADV\_NE)}$	FSMC_NEx low to FSMC_NADV low	1	2	ns
$t_{w(NADV)}$	FSMC_NADV low time	T_{HCLK}– 2	T_{HCLK}+ 2	ns
$t_{h(AD\_NADV)}$	FSMC_AD(adress) valid hold time after FSMC_NADV high)	T_{HCLK}	-	ns

Figure 76. SD default mode

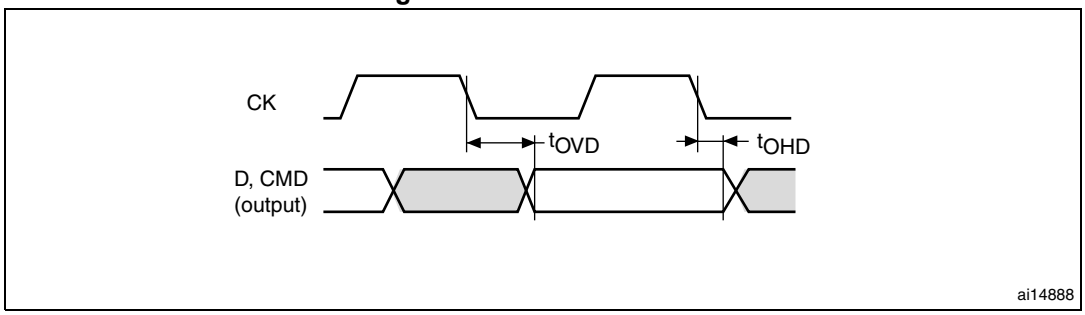


Table 85. SD/MMC characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
f_{PP}	Clock frequency in data transfer mode	$C_L \leq 30$ pF	0	48	MHz
-	SDIO_CK/f_{PCLK2} frequency ratio	-	-	8/3	-
$t_{W(CKL)}$	Clock low time, f_{PP} = 16 MHz	$C_L \leq 30$ pF	32	-	ns
$t_{W(CKH)}$	Clock high time, f_{PP} = 16 MHz	$C_L \leq 30$ pF	31	-	
t_r	Clock rise time	$C_L \leq 30$ pF	-	3.5	
t_f	Clock fall time	$C_L \leq 30$ pF	-	5	
CMD, D inputs (referenced to CK)					
t_{ISU}	Input setup time	$C_L \leq 30$ pF	2	-	ns
t_{IH}	Input hold time	$C_L \leq 30$ pF	0	-	
CMD, D outputs (referenced to CK) in MMC and SD HS mode					
t_{OV}	Output valid time	$C_L \leq 30$ pF	-	6	ns
t_{OH}	Output hold time	$C_L \leq 30$ pF	0.3	-	
CMD, D outputs (referenced to CK) in SD default mode(1)					
t_{OVD}	Output valid default time	$C_L \leq 30$ pF	-	7	ns
t_{OHD}	Output hold default time	$C_L \leq 30$ pF	0.5	-	

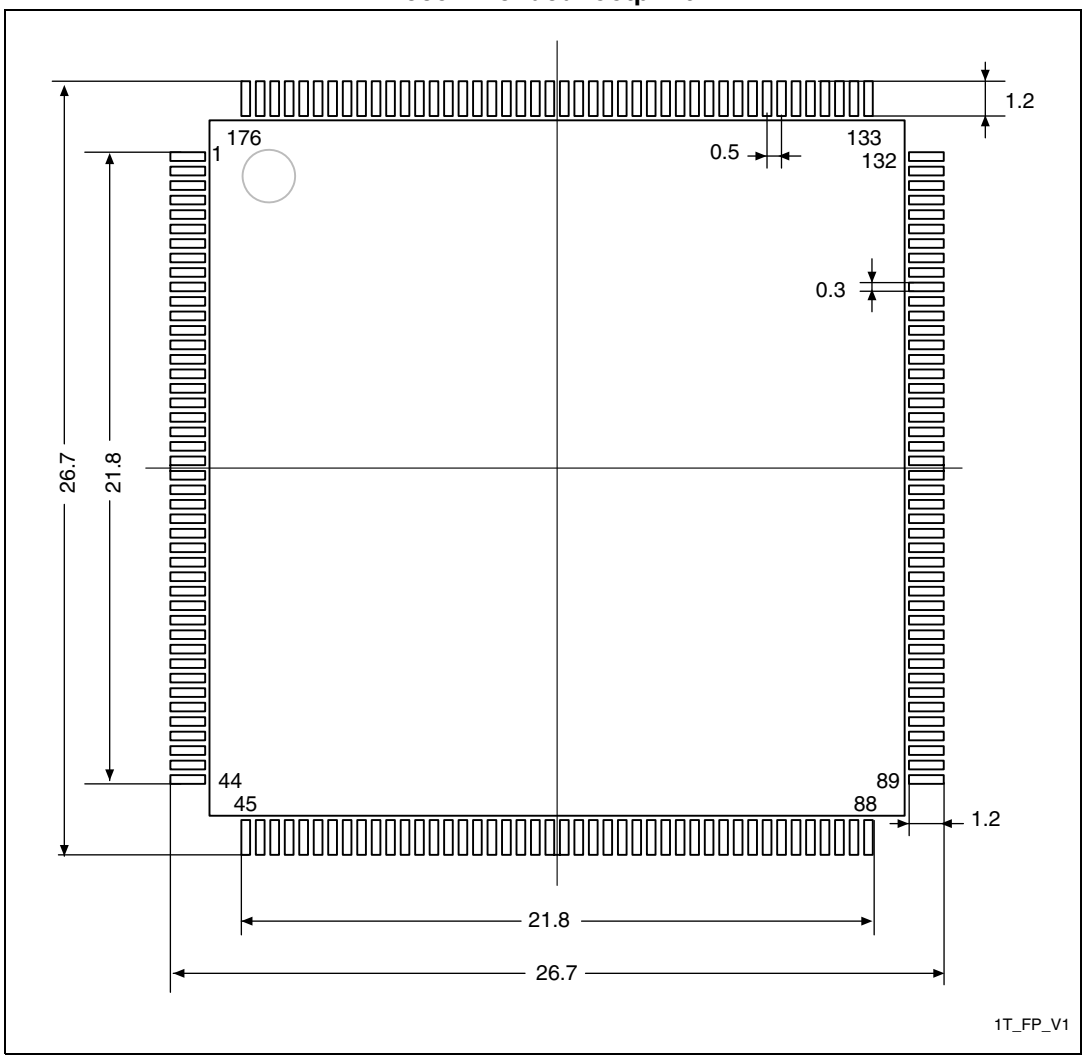
1. Refer to SDIO_CLKCR, the SDI clock control register to control the CK output.

6.3.28 RTC characteristics

Table 86. RTC characteristics

Symbol	Parameter	Conditions	Min	Max
-	f_{PCLK1}/RTCCLK frequency ratio	Any read/write operation from/to an RTC register	4	-

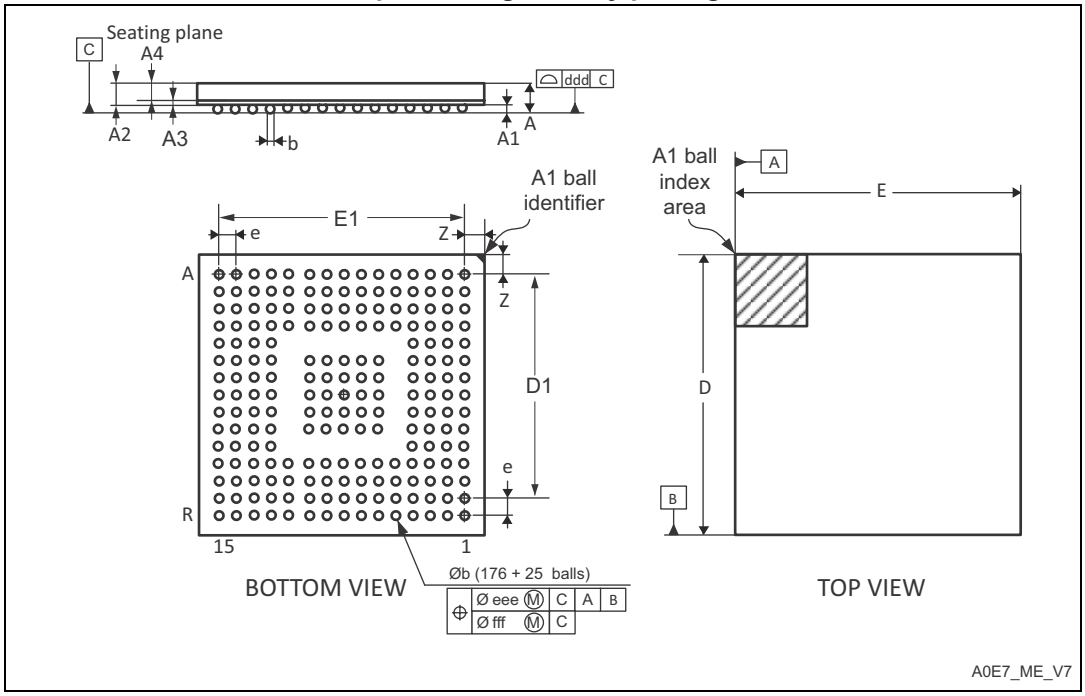
Figure 88. LQFP176 - 176-pin, 24 x 24 mm low profile quad flat package recommended footprint



1. Dimensions are expressed in millimeters.

7.6 UFBGA176+25 package information

Figure 89. UFBGA176+25 - 201-ball, 10 x 10 mm, 0.65 mm pitch, ultra fine pitch ball grid array package outline



1. Drawing is not to scale.

Table 93. UFBGA176+25, - 201-ball, 10 x 10 mm, 0.65 mm pitch, ultra fine pitch ball grid array package mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	0.600	-	-	0.0236
A1	-	-	0.110	-	-	0.0043
A2	-	0.450	-	-	0.0177	-
A3	-	0.130	-	-	0.0051	0.0094
A4	-	0.320	-	-	0.0126	-
b	0.240	0.290	0.340	0.0094	0.0114	0.0134
D	9.850	10.000	10.150	0.3878	0.3937	0.3996
D1	-	9.100	-	-	0.3583	-
E	9.850	10.000	10.150	0.3878	0.3937	0.3996
E1	-	9.100	-	-	0.3583	-
e	-	0.650	-	-	0.0256	-
Z	-	0.450	-	-	0.0177	-
ddd	-	-	0.080	-	-	0.0031

Table 97. Document revision history (continued)

Date	Revision	Changes
04-Nov-2013	11	In the whole document, updated notes related to WLCSP64+2 usage with IRROFF set to V_{DD}. Updated *Section 3.14: Power supply schemes*, *Section 3.15: Power supply supervisor*, *Section 3.16.1: Regulator ON* and *Section 3.16.2: Regulator OFF*. Added *Section 3.16.3: Regulator ON/OFF and internal reset ON/OFF availability*. Added note related to WLCSP64+2 package. Restructured RTC features and added reference clock detection in *Section 3.17: Real-time clock (RTC), backup SRAM and backup registers*. Added note indicating the package view below *Figure 10: STM32F20x LQFP64 pinout*, *Figure 12: STM32F20x LQFP100 pinout*, *Figure 13: STM32F20x LQFP144 pinout*, and *Figure 14: STM32F20x LQFP176 pinout*. Added *Table 7: Legend/abbreviations used in the pinout table*. *Table 8: STM32F20x pin and ball definitions*: content reformatted; removed indexes on V_{SS} and V_{DD}; updated PA4, PA5, PA6, PC4, BOOT0; replaced DCMI_12 by DCMI_D12, TIM8_CHIN by TIM8_CH1N, ETH_MII_RX_D0 by ETH_MII_RXD0, ETH_MII_RX_D1 by ETH_MII_RXD1, ETH_RMII_RX_D0 by ETH_RMII_RXD0, ETH_RMII_RX_D1 by ETH_RMII_RXD1, and RMII_CRS_DV by ETH_RMII_CRS_DV. *Table 10: Alternate function mapping*: replaced FSMC_BLN1 by FSMC_NBL1, added EVENTOUT as AF15 alternated function for PC13, PC14, PC15, PH0, PH1, and PI8. Updated *Figure 17: Pin loading conditions* and *Figure 18: Pin input voltage*. Added V_{IN} in *Table 14: General operating conditions*. Removed note applying to $V_{POR/PDR}$ minimum value in *Table 19: Embedded reset and power control block characteristics*. Updated notes related to C_{L1} and C_{L2} in *Section : Low-speed external clock generated from a crystal/ceramic resonator*. Updated conditions in *Table 41: EMS characteristics*. Updated *Table 42: EMI characteristics*. Updated V_{IL}, V_{IH} and V_{Hys} in *Table 46: I/O static characteristics*. Added *Section : Output driving current*and updated *Figure 39: I/O AC characteristics definition*. Updated $V_{IL(NRST)}$ and $V_{IH(NRST)}$ in *Table 49: NRST pin characteristics*, updated *Figure 39: I/O AC characteristics definition*. Removed tests conditions in *Section : I2C interface characteristics*. Updated *Table 52: I2C characteristics* and *Figure 41: I2C bus AC waveforms and measurement circuit*. Updated I_{VREF+} and I_{VDDA} in *Table 66: ADC characteristics*. Updated Offset comments in *Table 68: DAC characteristics*. Updated minimum $t_{h(CLKH-DV)}$ value in *Table 78: Synchronous non-multiplexed NOR/PSRAM read timings*.